#### Advanced Integrated Circuits and Systems Laboratory



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- Tufts ECE Highlights
- Overview of Lab Research Thrusts
- Broadband Optical Wireless
   Communication
- Flip-Chip Integrated Optical Receivers
- Research Areas of Interest
- Conclusions



### **Tufts ECE Department Highlights**

#### People

- 11 Faculty, 9 Adjunct Faculty
- 55 UG, 22 Grads
- Research Areas:
  - Analog/Mixed-Signal VLSI
  - Audio Engineering
  - Control Theory
  - Digital Signal & Image
     Processing
  - Fault Simulation
  - Information Coding and Theory

- Microwave Theory & Techniques
- mm-Wave Measurements
- Nanoscale Circuits & Systems
- Optical/RF Comms
- Plasma Engineering
- Sensor Electronics



### **Principal Investigator**

- MPhil and PhD, University of Cambridge (UK), 2003
  - Thesis: Integrated Circuit Design for Wireless Network Receivers
  - 1999 Marshall Scholar
  - NSF Graduate Research Fellow
  - 1999-2003 St. John's, Cambridge Scholar
- Assistant Professor, Tufts University, 2005-present
- VLSI Research Engineer, Information Sciences Institute, April 2004 – Sept. 2005
  - DARPA Radiation-Hardening-By-Design (RHBD) Program
  - Developed process monitor chips to track the radiation tolerance of commercial silicon processes (TF 130nm CMOS)
  - Novel RHBD techniques for implementation in silicon technologies

#### **Current Students and Affiliates**



- 2 MS, 2 PhD
- Visiting Research Scholar, Beijing Microelectronics Institute



## Integrated Circuit Design Curriculum

- EE103 Introduction to VLSI Design
- EE147 Analog and Mixed Signal MOS IC Design
- EE194 Devices and Circuits for Optical Communications
- EE148 Silicon Radio Frequency IC Design
- EE294 Advanced Analog Integrated Circuits
- EE117 Introduction to Microwave Devices
- EE118 Microwave Semi Devices and Circuits





- Extensive laboratory work using industry standard design tools (Example: Cadence tools, Agilent ADS, Ansoft HFSS)
- Final projects address real world design problems:
  - System to Silicon implementation
  - Chips fabricated by MOSIS in AMI 0.5u CMOS process
  - PCB design and testing part of the curriculum



# **Tufts Advanced Technologies Lab**

- Shared Interdisciplinary Facility
  - Sensors and Instrumentation Lab
  - ✓ Micro/Nano Fab
  - Biomimetic Devices Lab
  - ✓ Soft Materials
  - ✓ Tissue Engineering
  - ✓ Soft-Bodied Robots
  - Nanoscale Circuits Lab
  - ✓ Advanced Integrated Circuits and Systems Lab







### **Test and Measurement Facilities**

#### **DC and High Frequency Environment**

- Agilent 8510C Network Analyzer
- Anritsu MP1800A 12.5Gb/s Signal Quality Analyzer
- Agilent E4408B Spectrum Analyzer
- RF Cascade Probe station for die level testing
- Agilent and Instek Precision power supplies
- Agilent Precision digital multimeters
- Agilent High Bandwidth Mixed-Signal Oscilloscopes 54855A DSO
- Agilent High Speed Logic Analyzers 16702B
- Agilent Arbitrary Function Generators 8648B
- Weller Soldering Workstation
- ESD protected work-area

#### Optical Workbench for Testing and Characterization

- 10Gb/s, 1550nm Electro-optic Absorption Modulator
- Fiber Coupled Laser Source 1550nm, 1.5mW and Collimator
- Fabry-Perot Laser Diode and TEC Controller (200mA, 16W)
- Si and InGaAs photodetectors
- Optical breadboard, posts, mounting bases, and lens mounts
- Thorlabs Power Meter System with Ge Sensor
- Thorlabs XYZ Translation Stage
- Polarized HeNe Laser System



### Lab Research Thrusts

#### Broadband Optical Wireless Links

 Multi-Gb/s, Low-power optical transceivers for secure, high-speed data/sensor communication

#### **Biomedical Imaging**

- Imaging Receivers for frequencydomain optical mammography
  - Integrated microarrays for fluorescence detection

Optoelectronic Integrated Circuits

#### **RF and Optical Networks**

 High Performance ICs for integration of microwave wireless with the optical fiber backbone



#### Future Generation Communication Systems

21<sup>st</sup> Century Military/Commercial Communications will require network solutions combining wired and wireless systems

#### **Networked Manned and Unmanned Systems**



See *anything*... From *anywhere*.... At *anytime*...



# Free-Space Optical Communications brings added security and capacity

\* Dr. Steve Pappert, DARPA-MTO, "Electrons & Photons: You need both", March 2007

#### Why Optical Wireless?

#### <u>RF</u>

- Highly Regulated Spectrum → Low data rates (10s of Mb/s)
- High User Mobility, Long Range
- High Rx Sensitivity
- No obstruction

#### <u>Optical</u>

- Unregulated THz channels
- No EMI → Secure Channels
- WDM → Higher Aggregate Capacity
- Baseband Processing → Low-Power Compatibility
- LOS channels prone to blocking

Realistic optical wireless deployments that will deliver on the promise of the technology will require reconfigurable, ad-hoc mesh networks with multi-point/hybrid transceivers



#### Integrated System-in-Package Microsystems for Optical Wireless Metworks

**Metamaterials and PhC** for beam steering, filtering, waveguiding

III/V devices allow higher transmit powers and hybrid flip-chip integration

III/V Optoelectronic Device Arrays

**CMOS**: Sensitive analog circuits integrated with low-power back-end digital processing circuits

CMOS Transceiver, Signal Processing, CDR

Ceramic Package



### **Cellular Optical LAN Approach**

4-yr Research Partnership with promising results

- Integrated transceiver components
- Imaging optics to implement tracking
- Eye safe 1.3 1.5µm optical transmission



#### **Receiver Design Challenges**

Overall System Performance limited by Rx Bandwidth and Noise:

- Allowed Tx power level at 1550nm is 20x greater than at 880nm for Class 1 eye safety BUT
  - Long  $\lambda$  detectors have high C (typically 40-50pF/mm2)
  - Difficult to focus incoming radiation to allow small high bandwidth detectors
  - Typical design approaches for fiber-based receivers may not be
    optimal (C~50-100fF)



### **Receiver Design Challenges**

- Single element detector
  - $\rightarrow$  Large area for coverage
  - Poor bandwidth
  - Ambient noise
  - Noise performance degradation



Transimpedance Amplifier:
➢ For a given BW and Cin, achieves higher gain and better noise performance

$$f_{BW} \approx \frac{1 + A}{2\pi \cdot R_f C_{\rm pd}}$$



#### **Receiver Subsystem**



#### **Selector/Combiner Circuit**



# **CMOS Imaging Diversity Receiver**

- Selector/Combiner Circuit
  - Analog Signal Processing Circuits
  - Enables diversity combining increasing output SNR
- Flip-Chip:
  - III-V devices with low cost, low-power CMOS
  - Scalability



Segmented receiver chip to account for variable device yield

#### **CMOS Receiver Chip**



Alcatel 0.7µm CMOS

Post-processing & bump placement by PacTech

#### 100µm Sn-Pb bumps

**TIA Preamplifier Electrical Characterization**  $f_{-3\,db}$ =155 MHz Gain = 72.2 dB $\Omega$ Sens=-30 dBm @ BER=10<sup>-9</sup>  $(C_{pd}$ =6-10pF)

#### **Photodetector Device**



### **Flip-Chip Integration**



#### **Opto-Mechanics Integration**



#### **Selector-Combiner Results**

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#### Channel Weighting over 10dB range Unable to measure power at each channel

#### >1 Gb/s Operation in CMOS













#### Input Noise=14pA/rtHz @ 500MHz



**Common-Source** 

What is the optimal gain stage A for Stability and Power dissipation in CMOS?



#### **Self-Biased AGC Front-End Amplifier**

**OW** "mesh" require high dynamic range Rx ✓ Multipoint reception ✓ Accommodate variable link distance, signal amplitude, modulation formats

Technology	0.5µm AMI CMOS	
DC Gain	$50 dB\Omega - 38 dB$	
-3-dB Bandwidth	345MHz	
Power Dissipation	106mW	
Input Capacitance	6pF	
Chip Area	270µm x 125µm	
Input Referred Noise	12.5pA/√Hz	



#### 1-Gb/s Automatic Gain Control TIA with Common-mode Feedback

Gain Control achieved by tuning the resistance at the output
Control determined by on-chip peak detection circuit



# **AGC TIA Summary**

Technology	0.5µm AMI CMOS	
DC Gain	$53$ dB $\Omega$ – $38$ dB	
-3-dB Bandwidth	436.2MHz @ 5pF 548.8MHz @ 0.5pF	
<b>Power Dissipation</b>	41.3mW	
Chip Area	190µm x 160µm	
Input Referred Noise	27.3pA/√Hz @ 5pF 14.2pA/√Hz @ 0.5pF	



By: Yiling Zhang, MS candidate



# **1-Gb/s 30dB Limiting Amplifier with Active Inductor**



### **Limiting Amplifier Summary**

Technology	AMI $0.5 \mu m$		
Supply Voltage	3.3V		
Power Dissipation	130mW		
Chip Area	$232 * 320 \mu m^2$		
DC gain	30dB		
	Schematic	Post Layout	
Bandwidth(-3dB)	940MHz	695MH	
Data Bits	1.34Gb/s	1Gb/s	
Input Noise	-	$766 pv/\sqrt{Hz}$	



By: Ruida Yun, PhD candidate

### **Biomedical Imaging**

**CMOS Imaging Rx** Chip CMOS photodetectors Low-noise frontend for high sensitivity (nW) On-chip phase detection (<1 deg) AGC receiver to avoid optical overload



#### Integrated Micro-arrays for Fluorescence Detection

Silicon-based micro-arrays for high-throughput diagnostics and screening.



o How can circuit techniques for optical comms. enhance the detection process and increase sensitivity and selectivity?

o What types of photonic materials are best for integration with CMOS and for contact with living cells?



#### **Related Projects**

- Flip-chip Integrated Imaging Diversity Receivers
  - In collaboration with AFRL which provides expertise in custom InGaAs detector arrays with minimum pixel size of 15um x 15um.
  - Developing architecture for 24 x 24 CMOS imaging diversity Rx
- Multipoint CMOS Receiver Architectures for Optical Wireless Mesh Network Topologies
- Current-mode signal processing approaches to optical diversity combining



#### Conclusions

- Review of key design aspects of free-space optical links for broadband wireless communication.
- Presented the design and experimental results for a flip-chip integrated, imaging diversity receiver for use in a free-space optical link operating at 310 Mb/s.
- Demonstrated channel selection and equal gain combining.
- Presented design of a TIA accommodating 6pF detectors and implemented in 0.35um CMOS with good eye diagrams up to 1Gb/s.
- Presented design of a self-biased AGC TIA for use highly varying free-space optical channels.



#### **THANK YOU**

